

**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Shigao Chen  
Appl. No.: 10/821,461  
Filed: April 9, 2004  
Art Unit: 3737  
Title: METHOD AND APPARATUS FOR SHEAR PROPERTY  
CHARACTERIZATION FROM RESONANCE INDUCED BY  
OSCILLATORY RADIATION FORCE  
Examiner: Joel Lamprecht  
Docket No.: 630666.91063

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**AMENDMENT ACCOMPANYING REQUEST FOR CONTINUED EXAMINATION**

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MS Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In response to the Office Action dated Dec. 22, 2008, the Applicants submit the following amendments and remarks.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 6 of this paper.